

Search Notes

Application/Control No.

10/522,559

Examiner

SANG KIM

Applicant(s)/Patent under
Reexamination

DREFS ET AL.

Art Unit

3654

SEARCHED

Class	Subclass	Date	Examiner
242	541 541.4-.7 547	3/14/2007	SK

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
John Nguyen: 242/541.5	3/14/2007	SK